## Notice of References Cited

Application/Control No. 10/735,501	Applicant(s)/Pate Reexamination ONISHI ET AL.			
Examiner	Art Unit			
Matthew E Warren	2815	Page 1 of 1		

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,724,042	04-2004	Onishi et al.	257/341
	В	US-6,677,626	01-2004	Shindou et al.	257/266
	С	US-			
-	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	1,	US-			
	J	US-			
	κ	US-			
	L.	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001332726 A	11-2001	Japan	INOUE et al.	H01L 29/78
	0					
	Р					
	Q	· .				
	R					·
	S					
	Т				,	

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.